

STL16N65M5

N-channel 650 V, 0.270 Ω 12 A PowerFLAT™ 8x8 HV MDmesh™ V Power MOSFET

Features

Order code	V _{DSS} @ T _{Jmax}	R _{DS(on)} max	I _D
STL16N65M5	710 V	< 0.299 Ω	12 A ⁽¹⁾

- 1. The value is rated according to $R_{\text{thi-case}}$
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

Applications

Switching applications

Description

This device is an N-channel MDmesh™ V Power MOSFET based on an innovative proprietary vertical process technology, which is combined with STMicroelectronics' well-known PowerMESH™ horizontal layout structure. The resulting product has extremely low onresistance, which is unmatched among siliconbased Power MOSFETs, making it especially suitable for applications which require superior power density and outstanding efficiency.

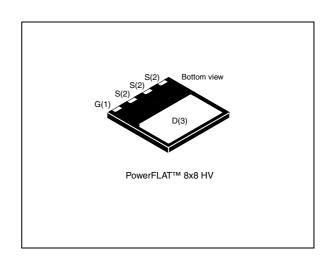


Figure 1. Internal schematic diagram

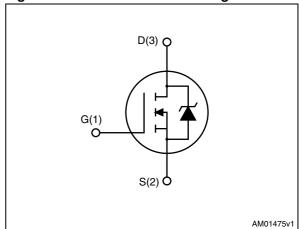


Table 1. Device summary

Order code	Marking	Package	Packaging
STL16N65M5	16N65M5	PowerFLAT™ 8x8 HV	Tape and reel

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STL16N65M5 Electrical ratings

1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage (V _{GS} = 0)	650	V
V _{GS}	Gate-source voltage	± 25	V
I _D ⁽¹⁾	Drain current (continuous) at T _C = 25 °C	12	Α
I _D ⁽¹⁾	Drain current (continuous) at T _C = 100 °C	7.4	Α
I _{DM} (1),(2)	Drain current (pulsed)	48	Α
I _D ⁽³⁾	Drain current (continuous) at T _{amb} = 25 °C	2	Α
I _D (3)	Drain current (continuous) at T _{amb} = 100 °C	1.3	Α
I _{DM} ^{(2),(3)}	Drain current (pulsed)	8	Α
P _{TOT} (3)	Total dissipation at T _{amb} = 25 °C	3	W
P _{TOT} ⁽¹⁾	Total dissipation at T _C = 25 °C	90	W
I _{AR}	Avalanche current, repetitive or not- repetitive (pulse width limited by T_j max)	4	Α
E _{AS}	Single pulse avalanche energy (starting $T_j = 25$ °C, $I_D = I_{AR}$, $V_{DD} = 50$ V)		mJ
dv/dt (4)	Peak diode recovery voltage slope	15	V/ns
T _{stg}	Storage temperature	- 55 to 150	°C
Tj	Max. operating junction temperature	150	°C

- 1. The value is rated according to $R_{\mbox{\scriptsize thj-case}}$
- 2. Pulse width limited by safe operating area
- 3. When mounted on FR-4 board of inch², 2oz Cu
- 4. $I_{SD} \leq$ 12 A, di/dt \leq 400 A/ μ s, V_{Peak} < $V_{(BR)DSS}$, V_{DD} = 400 V

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case max	1.38	°C/W
R _{thj-amb} ⁽¹⁾	Thermal resistance junction-amb max	45	°C/W

1. When mounted on 1inch² FR-4 board, 2 oz Cu

2 Electrical characteristics

(T_C = 25 °C unless otherwise specified)

Table 4. On /off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage (V _{GS} = 0)	I _D = 1 mA	650			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V _{DS} = 650 V V _{DS} = 650 V, T _C =125 °C			1 100	μ Α μ Α
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	V _{GS} = ± 25 V			100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	3	4	5	V
R _{DS(on)}	Static drain-source on resistance	$V_{GS} = 10 \text{ V}, I_D = 6 \text{ A}$		0.270	0.299	Ω

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V _{DS} = 100 V, f = 1 MHz, V _{GS} = 0	-	1250 30 3	-	pF pF pF
C _{o(tr)} ⁽¹⁾	Equivalent capacitance time related	V 01 500 V V	-	100	-	pF
C _{o(er)} ⁽²⁾	Equivalent capacitance energy related	$V_{DS} = 0$ to 520 V, $V_{GS} = 0$	-	30	-	pF
R _G	Intrinsic gate resistance	f = 1 MHz open drain	-	2	-	Ω
Q _g	Total gate charge	V _{DD} = 520 V, I _D = 6 A,		31		nC
Q_{gs}	Gate-source charge	V _{GS} = 10 V	-	8	-	nC
Q_{gd}	Gate-drain charge	(see Figure 16)		12		nC

^{1.} $C_{oss\,eg.}$ time related is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

^{2.} $C_{oss\ eq.}$ energy related is defined as a constant equivalent capacitance giving the same stored energy as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
t _d (v)	Voltage delay time	$V_{DD} = 400 \text{ V}, I_{D} = 8 \text{ A},$		25		ns
t _r (v)	Voltage rise time	$R_G = 4.7 \Omega$, $V_{GS} = 10 V$		7		ns
t _f (i)	Current fall time	(see Figure 17),	_	6	-	ns
t _c (off)	Crossing time	(see Figure 20)		8		ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current Source-drain current (pulsed)		-		12 48	A A
V _{SD} ⁽²⁾	Forward on voltage	$I_{SD} = 12 \text{ A}, V_{GS} = 0$	-		1.5	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} = 12 A, di/dt = 100 A/μs V _{DD} = 100 V (see <i>Figure 17</i>)	1	300 3.5 23		ns µC A
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 12 \text{ A, di/dt} = 100 \text{ A/µs}$ $V_{DD} = 100 \text{ V, T}_{j} = 150 \text{ °C}$ (see <i>Figure 17</i>)	-	350 4 24		ns μC A

^{1.} Pulse width limited by safe operating area

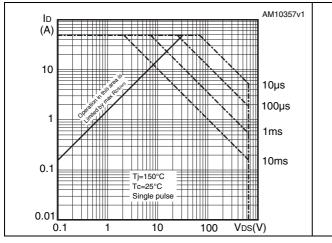
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^{2.} Pulsed: pulse duration = 300 μ s, duty cycle 1.5%

2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

Figure 3. Thermal impedance



Zth PowerFLAT 8x8 HV

0.2

0.1

0.05

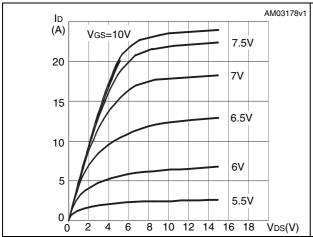
0.01

Single pulse

10²
10⁵
10⁴
10³
10²
tp(\$)

Figure 4. Output characteristics

Figure 5. Transfer characteristics



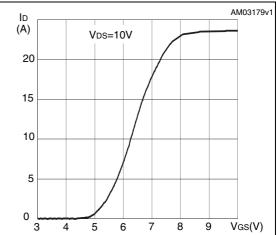
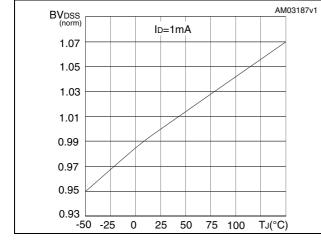


Figure 6. Normalized B_{VDSS} vs temperature

Figure 7. Static drain-source on resistance



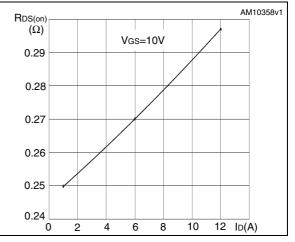


Figure 8. **Output capacitance stored energy** Figure 9. Capacitance variations AM03183v1 AM03312v1 (µJ) (pF) 10000 6 Ciss 1000 100 Coss 10 Crss V_{DS}(V) 100 200 300 400 500 600 V_{DS}(V) 10 100 0.1

Figure 10. Gate charge vs gate-source voltage Figure 11. Normalized on resistance vs temperature

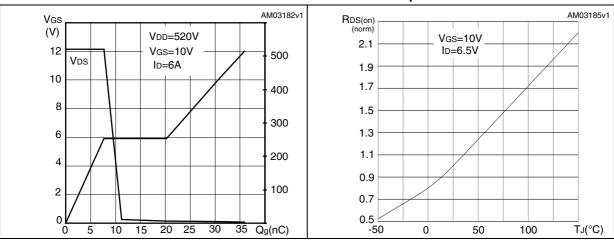
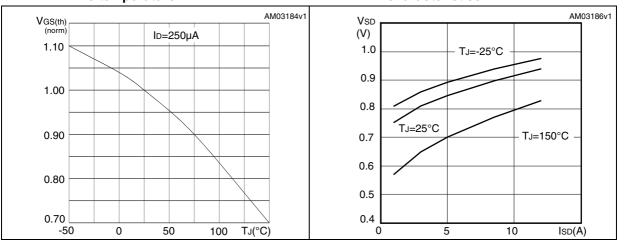
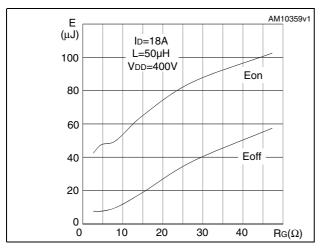


Figure 12. Normalized gate threshold voltage Figure 13. Source-drain diode forward vs temperature characteristics



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Figure 14. Switching losses vs gate resistance



1. Eon including reverse recovery of a SiC diode

STL16N65M5 Test circuits

3 Test circuits

Figure 15. Switching times test circuit for resistive load

Figure 16. Gate charge test circuit

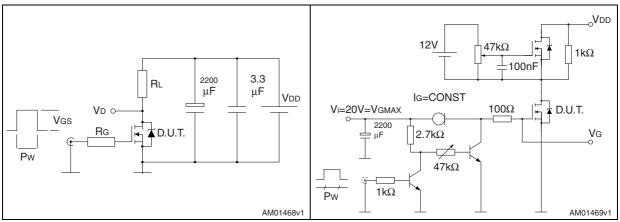


Figure 17. Test circuit for inductive load switching and diode recovery times

Figure 18. Unclamped inductive load test circuit

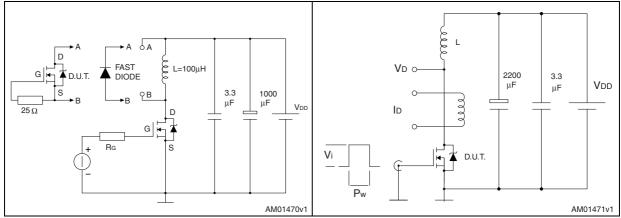
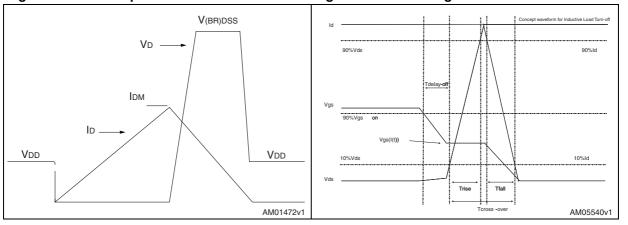


Figure 19. Unclamped inductive waveform

Figure 20. Switching time waveform



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4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

Table 8. PowerFLAT™ 8x8 HV mechanical data

Dim.		mm	
Dilli.	Min.	Тур.	Max.
Α	0.80	0.90	1.00
A1	0.00	0.02	0.05
b	0.95	1.00	1.05
D		8.00	
E		8.00	
D2	7.05	7.20	7.30
E2	4.15	4.30	4.40
е		2.00	
L	0.40	0.50	0.60
aaa		0.10	
bbb		0.10	
ccc		0.10	

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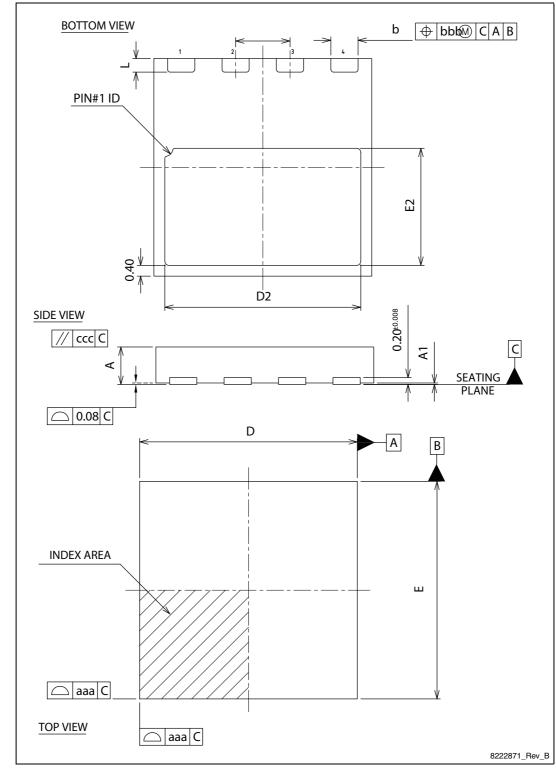


Figure 21. PowerFLAT™ 8x8 HV drawing mechanical data

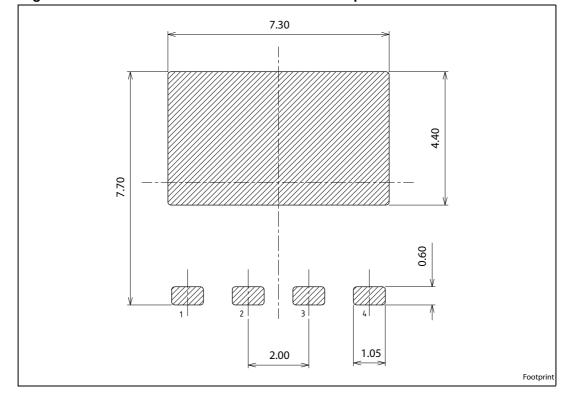


Figure 22. PowerFLAT™ 8x8 HV recommended footprint

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Revision history STL16N65M5

5 Revision history

Table 9. Document revision history

Date	Revision	Changes
30-Apr-2010	1	First release
08-Jun-2010	2	V _{GS} value has been changed in <i>Table 4</i>
10-Feb-2011	3	Modified R _{DS(on)} value
28-Jul-2011	4	Document status promoted from preliminary data to datasheet Added Section 2.1: Electrical characteristics (curves) Minor text changes
03-Nov-2011	5	Section 4: Package mechanical data has been modified.

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